## Notice of References Cited Application/Control No. 10/074,117 Applicant(s)/Patent Under Reexamination BUCHNER ET AL. Examiner SON P. HUYNH 2623 Applicant(s)/Patent Under Reexamination Reexamination BUCHNER ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-5,802,059	09-1998	Hayashi, Minobu	370/429	
*	В	US-6,588,017	07-2003	Calderone, Theodore	725/120	
*	С	US-2005/0028208	02-2005	Ellis et al.	725/058	
*	D	US-7,051,360	05-2006	Ellis et al.	725/136	
*	Е	US-2004/0172658	09-2004	Rakib et al.	725/120	
*	F	US-2002/0088002	07-2002	Shintani et al.	725/110	
*	G	US-7,150,032	12-2006	Sadanaka et al.	725/80	
*	Н	US-6,480,551	11-2002	Ohishi et al.	375/260	
*	ı	US-7,039,934	05-2006	Terakado et al.	725/37	
*	J	US-6,629,173	09-2003	Iijima, Yuko	710/107	
*	K	US-6,307,842	10-2001	Nakata et al.	370/254	
*	L	US-7,103,263	09-2006	Murayama et al.	386/83	
*	М	US-6,717,961	04-2004	Park, Tae Joon	370/538	

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.